

<sup>2</sup>H(<sup>80</sup>Ge,p)    [2019Ah05](#)

Type	Author	History	Citation	Literature Cutoff Date
Full Evaluation	M. Shamsuzzoha Basunia		NDS 199,271 (2025)	1-Sep-2024

Adopted/Edited the XUNDL dataset compiled by E.A. McCutchan (NNDC,BNL) December 8, 2020.  
<sup>80</sup>Ge beam, E=310 MeV, was produced at the Holifield Radioactive Ion Beam Facility and incident on a Cd<sub>n</sub> target (thickness 174 μg/cm<sup>2</sup>). Measured protons using various silicon detectors. Measured <sup>81</sup>Ge recoils with a fast ionization chamber.

<sup>81</sup>Ge Levels

E(level)	J <sup>π</sup>	L <sup>†</sup>	Comments
690 50	1/2 <sup>+</sup> & 5/2 <sup>+</sup>	0+1	E(level),J <sup>π</sup> : unresolved doublet associated with a 1/2 <sup>+</sup> state at 679 keV and a 5/2 <sup>+</sup> at 711 keV ( <a href="#">2019Ah05</a> ). Spectroscopic factor S: 0.27 11 for s <sub>1/2</sub> and 0.39 17 for d <sub>5/2</sub> .
1160 70			

<sup>†</sup> From DWBA fits to dσ/dΩ.